Search Notes	

 Application/Control No.	Applicant(s)/Patent under Reexamination	
09/886,064	HAITSMA ET AL.	
Examiner	Art Unit	_
Shin-Hon Chen	2131	

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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	6/29/2007	S.C.
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